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Name of Person Making Transmission: Robert Faber  
Signature: *Robert Faber*

DOCUMENT(S) FAXED:

PAGES ATTACHED: 12

Re Applic of	Anne Gattiker et al.
Docket No.	BUR920020068US1
Serial No.	10/539,247
Filing Date	06/16/2005
Attorney	Joseph P. Abate

Attached: Supplemental Information Disclosure Statement  
Form PTO-1449  
Copy of Ali Keshavarzi et al. Article

PLEASE DELIVER TO:  
EXAMINER: Unknown  
ART UNIT: 2820  
CONFIRMATION NO.: 9258  
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## INTERNATIONAL BUSINESS MACHINES CORPORATION

Intellectual Property Law  
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I hereby certify that this correspondence is being facsimile transmitted to: The Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313. The applicant and/or attorney requests the date of deposit as the filing date.

Name of Person Making Transmission: Robert Faber  
Date of Transmission: JUNE 9, 2006

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Robert Faber 6/9/06  
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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of _____:	Date: JUNE 8, 2006
Anne Gattiker et al. _____:	Group Art Unit: 2820
Serial No: 10/539,247 _____:	Examiner: Unknown
Filed: 06/16/2005 _____:	International Business Machines Corporation 2070 Route 52 Hopewell Junction, NY 12533

TITLE: INTEGRATED CIRCUIT TESTING METHODS USING WELL BIAS MODIFICATION

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

Pursuant to the duty of disclosure set forth in 37 C.F.R. 1.56, and further pursuant to the provisions of 37 C.F.R. 1.97 and 1.98, applicants hereby respectfully submit copies of the US and non-US patents and publications as listed on Form PTO-1449, attached hereto.

In citing these documents, no representation is made nor intended as to the pertinency or non-pertinency of the art, that better art than that listed is not available, or that other art is not applicable.

The Commissioner is hereby authorized to charge any and all fees for this submission to Deposit Account No. 09-0458.

Respectfully submitted,  
Anne Gattiker et al.

By

Joseph P. Abate 6-08-06  
Attorney for Applicant  
Registration No. 30,238  
Telephone No. 845-894-4633  
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10/539,247

BUR920020068US1

**INFORMATION DISCLOSURE CITATION**

(Use several sheets if necessary)

Docket Number (Optional)

BUR920020068US1

Application Number

10/539,247

Applicant(s)

Anne Gattiker et al.

Filing Date

June 16, 2005

Group Art Unit

2820

**U.S. PATENT DOCUMENTS**

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

**U.S. PATENT APPLICATION PUBLICATIONS**

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

**FOREIGN PATENT DOCUMENTS**

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO

**OTHER DOCUMENTS**

(Including Author, Title, Date, Pertinent Pages, Etc.)

		Ali Keshavarzi et al., "Intrinsic Leakage in Low Power Deep Submicron CMOS ICs". International Test Conference 1997 (IEEE Cat. No. 97CH36126), pp. 146-155.

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.